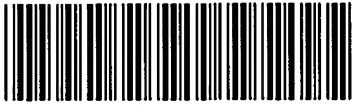


Search Notes

Application/Control No.

10/779,779

Examiner

Wen-Ying P. Chen

Applicant(s)/Patent under
Reexamination

NIIYA, HIROTAKE

Art Unit

2871

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Reviewed previously cited references	11/17/2005	WPC
Citations search of tagged references	11/17/2005	WPC